



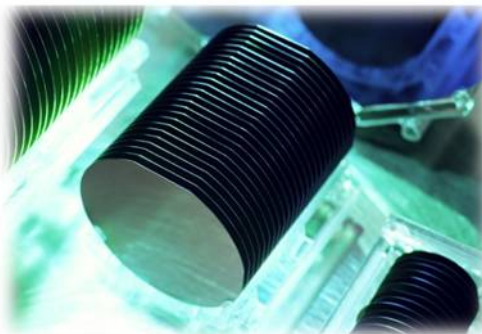
## Bulk (Free Standing) Gallium Nitride (GaN)

Semi-Insulating

Marco-Defect Density <10/cm<sup>2</sup>

Substrate Diameter N/A

Thickness 430μm



**Bulk (Free Standing) Gallium Nitride (GaN)**

refer to a thin layer of single crystalline GaN,

typically with thickness less Than 100 microns,

epitaxial grown on a foreign substrate, e.g. sapphire. Comparing with free standing GaN

substrate, GaN is only an alternative solution to device makers and its technical merit is

limited. Upon high volume and low cost production, however, GaN can replace sapphire in

LED manufacturing, enhancing up to 50% capacity of downstream MOCVD reactors.

Furthermore, GaN usually has lower dislocation density than MOCVD GaN grown on

sapphire. This is a favorable factor for UV devices as it is more sensitive to dislocation

density than blue LED does.

<b>Bulk (Free Standing) Gallium Nitride (GaN) Specifications</b>			
Thickness (μm)	430	Substrate Diameter	N/A
Off-Cut Angle (Degree)	0.2 off c-plane	GaN Line	Semi-Insulating
Marcodefect Density:	<10/cm <sup>2</sup>	Thickness Variation (±μm)	5
Carrier concentration (cm <sup>-3</sup> )	N/A	Resistivity (Ω·cm)	10 <sup>9</sup> -10 <sup>12</sup>
FWHM of (102) XRD arcsec	<300	Dislocation density	5E+6 cm <sup>-2</sup>
Surface finishing	Epi-ready (RMS<0.5nm)	Substrates	N/A
Bow (μm)	5	Package	Vacuum

Free Standing GaN Marco-Defect Density <10/cm<sup>2</sup> Thickness 430μm